



mai 25, 2010

EdXact enhances parasitics reduction, analysis tools

By Anne-Francoise Pele

PARIS — Post-layout verification specialist EdXact SA said it will release version 5.0 of Jivaro netlist reduction platform for analog circuits and version 3.2 of Comanche post-layout analysis tool at this year's DAC in Anaheim. Enhancements include interactive debugging capabilities, hierarchical file handling and improved selectivity features.

EdXact (Grenoble, France) said version 5.0 of Jivaro enables to group parasitics by property so as to remodel them selectively.

Version 5.0 also features enhancements on EdXact's PathFinder algorithm, a selectivity feature to accelerate simulation time, the company claimed.

In parallel, EdXact noted that version 3.2 of Comanche allows to interactively debug parasitics-related problems based on a graphical layout view in Cadence Virtuoso design environment, or in SpringSoft's Laker design environment.

The company added that Comanche 3.2 includes a new toolbox that generates statistics on a net-per-net basis and allows to compare two different extracted netlists.

TechOnline Communities

Audio DesignLine | Automotive DesignLine | CommsDesign | Digital Home DesignLine | DSP DesignLine | EDA DesignLine
 eeProductCenter | Embedded Internet | Green SupplyLine | Industrial Control DesignLine | Mobile Handset DesignLine | Planet Analog | Power Management DesignLine
 Programmable Logic DesignLine | RF DesignLine | Teardown.com | TechOnline | Video/Imaging DesignLine | Wireless Net DesignLine

EE Times

United States | Asia | China | Europe | France | Germany | India | Japan | Korea | Taiwan | United Kingdom | EE Times Supply Network

Additional Network Sites

Analog Europe | Automotive Designline Europe | DeepChip | Design & Reuse | Elektronik iNorden | Embedded.com
 | Microwave Engineering Europe | Portelligent | Power Management Designline Europe
 The RF Edge | Semiconductor Insights | Embedded-europe.com | Mechanical Design | TechOnline India

All materials on this site Copyright © 2010 EE Times Group, a Division of United Business Media LLC All rights reserved.

[Privacy Statement](#) | [Terms of Service](#)